L Number	Hits	Search Text	DB	Time stamp
-	109	(current adj transformer) with calibrat\$4	USPAT;	2003/11/24 15:51
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
	2	("4356721").PN.	USPAT;	2002/08/26 08:51
	_	*	US-PGPUB;	
	•		EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	139	(current adj transformer) with calibrat\$4	USPAT;	2003/11/24 15:52
		(various and management) with contrast .	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
	14038	electricity and meter	USPAT;	2003/11/24 16:59
-	14036	electricity and meter	US-PGPUB;	2003/11/24 10:37
			EPO; JPO;	
			DERWENT;	
	500	(electricity same meter) and (current or amperage or amp) and (volt or	IBM_TDB USPAT;	2003/11/24 15:55
-	598		US-PGPUB;	2003/11/24 13.33
	į i	voltage or potential) and transformer		
			EPO; JPO;	
-	ĺ		DERWENT;	
	22.500.4	204/9 1 240/9 1 702/9 1	IBM_TDB	2003/11/24 17:05
-	236094	324/\$.ccls. or 340/\$.ccls. or 702/\$.ccls.	USPAT;	2003/11/24 17.03
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	2003/11/24 17:01
-	303	revenue with meter	USPAT;	2003/11/24 17:01
			US-PGPUB;	
			EPO; JPO;	
	ĺ		DERWENT;	
		A section of the sect	IBM_TDB	2003/11/24 17:02
-	1337	((power or electricity or electric or revenue) with meter) and (electricity or	USPAT;	2003/11/24 17.02
1		current or voltage or volt or power) and transformer and (324/\$.ccls. or	US-PGPUB;	
		340/\$.ccls. or 702/\$.ccls.)	EPO; JPO;	
			DERWENT;	
	İ	A solid wasted and (classicity on	IBM_TDB	2002/11/24 17:04
	311		USPAT; US-PGPUB;	2003/11/24 17:04
		current or voltage or volt or power) and transformer and (324/\$.ccls. or		
		340/\$.ccls. or 702/\$.ccls.)) and ((calibrat\$4 or correct\$4 or compensat\$4)	EPO; JPO;	
		same transformer)	DERWENT;	
		((()	IBM_TDB	2003/11/24 17:05
-	311	((((power or electricity or electric or revenue) with meter) and (electricity or	USPAT;	2003/11/24 17:05
		current or voltage or volt or power) and transformer and (324/\$.ccls. or	US-PGPUB;	
		340/\$.ccls. or 702/\$.ccls.)) and ((calibrat\$4 or correct\$4 or compensat\$4)	EPO; JPO;	
,		same transformer)) and (current or amps or amperage or volt or voltage or	DERWENT;	
		potential)	IBM_TDB	2002/11/24 17 07
-	4016		USPAT;	2003/11/24 17:07
		(340/870.02) or (340/870.04) or (702/60) or (702/61) or (702/65)).CCLS.	US-PGPUB;	•
			EPO; JPO;	
	!		DERWENT;	
			IBM_TDB	2002/11/24 17 22
-	150	(((((power or electricity or electric or revenue) with meter) and (electricity or	USPAT;	2003/11/24 17:38
ļ		current or voltage or volt or power) and transformer and (324/\$.ccls. or	US-PGPUB;	
		340/\$.ccls. or 702/\$.ccls.)) and ((calibrat\$4 or correct\$4 or compensat\$4)	EPO; JPO;	
		same transformer)) and (current or amps or amperage or volt or voltage or	DERWENT;	
		potential)) and (((324/74) or (324/141) or (324/142) or (324/86) or	IBM_TDB	
	1	(340/870.01) or (340/870.02) or (340/870.04) or (702/60) or (702/61) or		
_		(702/65)).CCLS.)	<u> </u>	<u> </u>

	10	((((((power or electricity or electric or revenue) with meter) and (electricity	USPAT:	2003/11/24 18:20
		or current or voltage or volt or power) and transformer and (324/\$.ccls. or	US-PGPUB;	
		340/\$.ccls. or 702/\$.ccls.)) and ((calibrat\$4 or correct\$4 or compensat\$4)	EPO; JPO;	
		same transformer)) and (current or amps or amperage or volt or voltage or	DERWENT;	
		potential)) and (((324/74) or (324/141) or (324/142) or (324/86) or	IBM TDB	
}		(340/870.01) or (340/870.02) or (340/870.04) or (702/60) or (702/61) or		
		(702/65)).CCLS.)) and ((memory or eprom or eprom or prom or ram) with		
		factor)	Ì	
-	9	("3732489" "4837504" "5469049" "5548527" "5742512" "5924051" "6133720" "6256128" "6459258").PN.	USPAT	2003/11/24 17:57
_	7	((((((power or electricity or electric or revenue) with meter) and (electricity	USPAT:	2003/11/24 18:20
	1	or current or voltage or volt or power) and transformer and (324/\$.ccls. or	US-PGPUB;	
		340/\$.ccls. or 702/\$.ccls.)) and ((calibrat\$4 or correct\$4 or compensat\$4)	EPO; JPO;	
		same transformer)) and (current or amps or amperage or volt or voltage or	DERWENT;	
1		potential)) and (((324/74) or (324/141) or (324/142) or (324/86) or	IBM TDB	
		(340/870.01) or (340/870.02) or (340/870.04) or (702/60) or (702/61) or	_	
		(702/65)).CCLS.)) and ((memory or eprom or eeprom or prom or ram) with	1	
		transformer)		
	5	(("55444089") or ("5933004") or ("6112158")).PN.	USPAT;	2003/11/24 18:38
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM TDB	

CLASS 324 ELECTRICITY: MEASURING AND TESTING

300	PARTICLE PRECESSION RESONANCE
301	. Using a magnetometer
302	To determine direction
303	. Using well logging device
304	. Using optical pumping or sensing device
305	Having particular optical cell structure
306	. Determine fluid flow rate
307	. Using a nuclear resonance spectrometer system
308	Including a test sample and control sample
309	To obtain localized resonance within a sample
310	By scanning sample frequency spectrum
311	With signal decoupling
312	By spectrum storage and analysis
313	Including polarizing magnetic field/radio frequency tuning
314	With conditioning of transmitter signal
315	With sample resonant frequency and temperature interdependence
316	. Using an electron resonance spectrometer system
317	Including a test sample and control sample
318	. Spectrometer components
319	Polarizing field magnet
320	With homogeneity control
321	Sample holder structure
322	Electronic circuit elements
323	OF GEOPHYSICAL SURFACE OR SUBSURFACE IN SITU
324	. Including borehole fluid investigation
325	To determine fluid entry
326	. For small object detection or location
327	Using oscillator coupled search head
328	Of the beat frequency type
329	Using movable transmitter and receiver
330	. By aerial survey
331	For magnetic field detection
332	 With radiant energy or nonconductive-type transmitter
333	Within a borehole
334	With separate pickup
335	Employing multiple frequencies
336	To detect transient signals
337	To detect return wave signals
338	Within a borehole
339	By induction logging
340	To measure susceptibility

341	To measure dielectric constant
342	Using a toroidal coil
343	Using angularly spaced coils
344	 With radiant energy or nonconductive-type receiver
345	. By magnetic means
346	Within a borehole
347	 Using electrode arrays, circuits, structure, or supports
348	 For detecting naturally occurring fields, currents, or potentials
349	Of the telluric type
350	Including magneto-telluric type
351	Within a borehole
352	Combined with artificial source measurement
353	With fluid movement or pressure variation
354	Coupled to artificial current source
355	Within a borehole
356	While drilling
357	 Including separate pickup of generated fields or potentials
358	With three electrodes
359	With nonelectrode pickup means
360	Using a pulse-type current source
361	With mechanical current reversing means
362	To measure induced polarization
363	By varying the path of current flow
364	Using frequency variation
365	Offshore
366	For well logging
367	Using a pad member
368	Cased borehole
369	While drilling
370	Using surface current electrodes
371	Using plural fields
372	Between spaced boreholes
373	Using current focussing means
374	·. Including a pad member
375	· Including plural current focussing arrays
376	OF SUBSURFACE CORE SAMPLE
377	. For magnetic properties
378	INTERNAL-COMBUSTION ENGINE IGNITION SYSTEM OR DEVICE
379	. With analysis of displayed waveform
380	. Electronic ignition system
381	With magnetically controlled circuit
382	With capacitor discharge circuit
383	 By simulating or substituting for a component under test
384	. Using plural tests in a conventional ignition system

385	. Distributor
386	Dwell (i.e., cam angle)
387	Condenser
388	. Coil
389	. Magneto
390	. Low or high tension lead
391	. Ignition timing
392	Using a pulse signal technique
393	. In situ testing of spark plug
394	With cathode-ray tube display
395	Using an illuminating device to indicate spark plug condition
396	With an air gap in series with spark plug to indicate spark plug condition
397	By shorting the plug to ground to indicate spark plug condition $% \left(1\right) =\left(1\right) \left(1\right) +\left(1\right) \left(1\right) \left(1\right) +\left(1\right) \left(1$
398	With air gap in ground circuit
399	Wherein a measured electric quantity indicates spark plug condition
400	. Spark plug removed or tested in a test fixture
401	Using a pressure chamber
402	. Apparatus for coupling a measuring instrument to
	an ignition system
403	ELECTRIC LAMP OR DISCHARGE DEVICE
404	. Cathode-ray tube
405	. Vacuum tube
406	Plural tubes in the testing circuit
407	Testing circuit for diverse-type tube
408	Circuit for making diverse test
409	Testing discharge space characteristic (e.g., emission)
410	With application of current or potential to the discharge control means
411	 Pulsating or alternating current or potential for the discharge control means
412	Pulsating or alternating current for the anode
413	Shock testing
414	. Electric lamp
415	ELECTROMECHANICAL SWITCHING DEVICE
416	. Voltage regulator
417	. Thermostat switch
418	. Relay
419	Reed switch
420	To evaluate contact chatter
421	To evaluate contact resistance
422	To evaluate contact sequence of operation
423	To evaluate contact response time
424	. Circuit breaker
425	ELECTROLYTE PROPERTIES
426	. Using a battery testing device

427	To determine ampere-hour charge capacity
428	Including an integrating device
429	To determine load/no-load voltage
430	To determine internal battery impedance
431	With temperature compensation of measured condition
432	To determine battery electrolyte condition
433	To compare battery voltage with a reference voltage
434	To determine plural cell condition
435	Having particular meter scale or indicator
436	Including oscillator in measurement circuit
437	Including probe structure
438	. Using a pH determining device
439	. Using a conductivity determining device
440	Which includes a dropping mercury cell
441	Which includes a temperature responsive element
442	Which includes an oscillator
443	Having a bridge circuit
444	Which includes current and voltage electrodes
445	Having inductance probe structure
446	Having conductance probe structure
447	With movable or adjustable electrode
448	With concentric electrodes
449	With axially arranged electrodes
450	Which includes particular cell container
450	structure
450	•
	structure A MATERIAL PROPERTY USING
451	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid
451 452	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON
451 452 453	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid
451 452 453 454	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON . In a liquid . Frictionally induced
451 452 453 454 455	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced
451 452 453 454 455 456	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection
451 452 453 454 455 456 457	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD
451 452 453 454 455 456 457 458	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer
451 452 453 454 455 456 457 458 459	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS
451 452 453 454 455 456 457 458 459 460	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure
451 452 453 454 455 456 457 458 459 460 461	structure A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance
451 452 453 454 455 456 457 458 459 460 461 462	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions
451 452 453 454 455 456 457 458 459 460 461 462 463	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using electronegative gas sensor
451 452 453 454 455 456 457 458 459 460 461 462 463 464	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using a filter
451 452 453 454 455 456 457 458 459 460 461 462 463 464 465	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using electronegative gas sensor
451 452 453 454 455 456 457 458 459 460 461 462 463 464 465 466	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using a filter
451 452 453 454 455 456 457 458 459 460 461 462 463 464 465 466 467	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using a filter Using test material desorption
451 452 453 454 455 456 457 458 459 460 461 462 463 464 465 466 467 468	A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON In a liquid Frictionally induced Corona induced For flaw detection ELECTROSTATIC FIELD Using modulation-type electrometer USING IONIZATION EFFECTS For monitoring pressure Using a radioactive substance Using thermionic emissions Using a magnetic field For analysis of gas, vapor, or particles of matter Using a filter Using test material desorption Using thermal ionization

201	. Susceptibility
202	. Calibration
203	. Curie point determination
204	. Fluid material examination
205	. Permanent magnet testing
206	. Movable random length material measurement
207.11	. Displacement
207.12	Compensation for measurement
207.13	Having particular sensor means
207.14	Diverse sensors
207.15	Inductive
207.16	Electrically energized
	Separate pick-up
207.18	
207.19	
207.2	Hall effect
207.21	Magnetoresistive
207.22	
207.23	
207.24	
207.25	
207.26	Approach or retreat
209	. Stress in material measurement
210	. Magnetic information storage element testing
211	Memory core storage element testing
212	Dynamic information element testing
213	. Magnetic recording medium on magnetized object records object field
214	. By paramagnetic particles
215	With pattern enhancing additive
216	Flaw testing
217	. Railroad rail flaw testing
218	Rail joint cutout
219	. Magnetic sensor within material
220	Sensor supported, positioned, or moved within pipe
221	Borehole pipe testing
222	. Hysteresis or eddy current loss testing
223	. Hysteresis loop curve display or recording
224	. With temperature control of material or element of test circuit
225	. With compensation for test variable
226	. Combined
227	. Plural tests
228	. With means to create magnetic field to test material
229	Thickness measuring
230	Layer or layered material
231	With backing member
222	Plural magnetic fields in material

233	With phase sensitive element
234	Electrically energized nonforce type sensor
235	Noncoil type
236	Oscillator type
237	Material flaw testing
238	Material flaw testing
239	Induced voltage-type sensor
240	Material flaw testing
241	Opposed induced voltage sensors
242	Plural sensors
243	Plural sensors
244	. Magnetometers
244.1	Optical
245	Plural sensor axis misalignment correction
246	With means to align field sensor with magnetic field sensed
247	Nonparallel plural magnetic sensors
248	Superconductive magnetometers
249	Thin film magnetometers
250	Electronic tube or microwave magnetometers
251	Hall plate magnetometers
252	Semiconductor type solid-state or magnetoresistive magnetometers
253	Saturable core magnetometers
254	Second harmonic type
255	Peak voltage type
256	Energized movable sensing coil magnetometers
257	Moving coil magnetometer
258	Fixed coil magnetometer
259	Movable magnet or magnetic member interacts with magnetic field
260	. Magnetic field detection devices
261	With support for article
262	. Magnetic test structure elements
263	. Current through test material forms test magnetic field
500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
501	. Using radiant energy
502	. In an ignitor or detonator
503	. In vehicle wiring
504	With trailer
505	Combined with window glass
506	. Combined with a flashlight
507	With fuse testing attachment
508	. With electric power receptacle for line wire testing
509	. Of ground fault indication
510	 Of electrically operated apparatus (power tool, appliance, machine, etc.)

511	 Of electrically operated apparatus (power tool, appliance, machine, etc.)
512	. For fault location
513	Where component moves while under test
514	By exposing component to liquid or gas while under test
515	Using a particular sensing electrode
516	Metal chain
517	Wire bristles
518	Metal pellets or beads
519	By capacitance measuring
520	By frequency sensitive or responsive detection
521	By phase sensitive or responsive detection
522	By voltage or current measuring
523	Of an applied test signal
524	Polarity responsive
525	By resistance or impedance measuring
526	Using a bridge circuit
527	By applying a test signal
528	Tracing test signal to fault location
529	Using a magnetic field sensor
530	Using an electric field sensor
531	At fault site
532	Using time measuring
533	Of reflected test signal
534	By reflection technique
535	By time measuring
536	By spark or arc discharge
537	. Of individual circuit component or element
750	 System sensing fields adjacent device under test (DUT)
751	Using electron beam probe
752	Using light probe
753	Using electro-optic device
754	With probe elements
755	 Internal of or on support for device under test (DUT)
756	Contact confirmation
757	Probe contact enhancement
758	Probe alignment or positioning
759	With recording of test results on DUT
760	With temperature control
761	Pin
762	Cantilever
763	DUT including test circuit
764	With identification of DUT
765	Test of semiconductor device
766	With barrier layer
767	Diode
768	Bipolar transistor

769	Field effect transistor
770	Liquid crystal device test
771	Power supply test
772	Motor or generator fault tests
538	Electrical connectors
539	Multiconductor cable
540	With sequencer
541	For insulation fault
542	Having a light or sound indicator
543	Single conductor cable
544	For insulation fault
545	Armature or rotor
546	Winding or coil
547	Transformer
548	Capacitor
549	Resistor
550	Fuse
551	Insulation
552	Bushing
553	Oil
554	Sheet material
555	. Instruments and devices for fault testing
556	Having a lamp or light indicator
557	FOR INSULATION FAULT OF NONCIRCUIT ELEMENTS
558	. Where element moves while under test
559	. Where a moving sensing electrode scans a stationary element under test
	Stationary element under test
600	IMPEDANCE, ADMITTANCE OR OTHER
600	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL
600	IMPEDANCE, ADMITTANCE OR OTHER
	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS . Calibration . With auxiliary means to condition
601	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration
601 602	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS . Calibration . With auxiliary means to condition stimulus/response signals
601 602 603	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation
601 602 603 604	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit
601 602 603 604 605	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing
601 602 603 604 605 606	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A)
601 602 603 604 605 606 607	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process
601 602 603 604 605 606 607	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function
601 602 603 604 605 606 607	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing
601 602 603 604 605 606 607 608 609 610	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing Including a bridge circuit Including a remote type circuit Parameter related to the reproduction or fidelity of a signal affected by a circuit under test
601 602 603 604 605 606 607 608 609 610	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing Including a bridge circuit Including a remote type circuit Parameter related to the reproduction or fidelity of a signal affected by a circuit under test Noise
601 602 603 604 605 606 607 608 609 610 611 612	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing Including a bridge circuit Including a remote type circuit Parameter related to the reproduction or fidelity of a signal affected by a circuit under test
601 602 603 604 605 606 607 608 609 610 611 612	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing Including a bridge circuit Including a remote type circuit Parameter related to the reproduction or fidelity of a signal affected by a circuit under test Noise Signal to noise ratio or noise figure Transfer function type characteristics
601 602 603 604 605 606 607 608 609 610 611 612	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS Calibration With auxiliary means to condition stimulus/response signals For excitation Including marker signal generator circuit For response signal evaluation or processing Including a signal comparison circuit Including a conversion (e.g., A->D or D-> A) process Including a ratiometric function For sensing Including a bridge circuit Including a remote type circuit Parameter related to the reproduction or fidelity of a signal affected by a circuit under test Noise Signal to noise ratio or noise figure

618	Transient response or transient recovery time (e.g., damping)
619	Selective type characteristics
620	Distortion
621	Envelope delay
622	Phase
623	Harmonic
624	Intermodulation
625	Dissymmetry or asymmetry
626	Nonlinearity
627	Shielding effectiveness (SE)
628	Circuit interference (e.g., crosstalk) measurement
629	. Distributive type parameters
630	Plural diverse parameters
631	Using wave polarization (e.g., field rotation)
632	 Using particular field coupling type (e.g., fringing field)
633	Using resonant frequency
634	To determine water content
635	To determine dimension (e.g., distance or thickness)
636	With a resonant cavity
637	Using transmitted or reflected microwaves
638	 Scattering type parameters (e.g., complex reflection coefficient)
639	Where energy is transmitted through a test substance
640	To determine water content
641	To determine insertion loss
642	Where energy is reflected (e.g., reflectometry)
643	To determine water content
644	 To determine dimension (e.g., distance or thickness)
645	Having standing wave pattern
646	To determine reflection coefficient
647	Using a comparison or difference circuit
648	With a bridge circuit
649	. Lumped type parameters
650	Using phasor or vector analysis
651	With a bridge circuit
652	Of a resonant circuit
653	For figure of merit or Q value
654	Using inductive type measurement
655	Including a tuned or resonant circuit
656	Including a comparison or difference circuit
657	Using a bridge circuit
658	Using capacitive type measurement
659	With loss characteristic evaluation
660	With variable electrode area

661	 With variable distance between capacitor electrodes
662	To determine dimension (e.g., thickness or distance)
663	Where a material or object forms part of the dielectric being measured
664	To determine water content
665	By comparison or difference circuit
666	Including a bridge circuit
667	By frequency signal response, change or processing circuit
668	·. Including a tuned or resonant circuit
669	With compensation means
670	For temperature variations
671	 To determine dimension (e.g., dielectric thickness)
672	By comparison or difference circuit
673	Including a bridge circuit
674	By frequency signal response, change or processing circuit
675	Including a tuned or resonant circuit
676	With pulse signal processing circuit
677	Including R/C time constant circuit
678	Including charge or discharge cycle circuit
679	With comparison or difference circuit
680	Including a bridge circuit
681	 With frequency signal response, change or processing circuit
682	Including a tuned or resonant circuit
683	With phase signal processing circuit
684	With compensation means
685	For temperature variation
686	With a capacitive sensing means
687	Having fringing field coupling
688	Including a guard or ground electrode
689	To determine water content
690	Including a probe type structure
691	Using resistance or conductance measurement
692	 With living organism condition determination using conductivity effects
693	 With object or substance characteristic determination using conductivity effects
694	To determine water content
695	Where the object moves while under test
696	With a probe structure
697	For interface
698	To determine oil qualities
699	 To determine dimension (e.g., distance or thickness)
700	Including corrosion or erosion
701	Where the object moves while under test

702	With radiant energy effects
703	Including heating
704	With ratio determination
705	With comparison or difference circuit
706	Including a bridge circuit
707	With frequency response, change or processing circuit
708	Including a tuned or resonant circuit
709	With phase signal processing circuit
710	With phase signal processing circuit
711	Including R/C time constant circuit
712	Including a digital or logic circuit
713	With voltage or current signal evaluation
714	Including a potentiometer
715	Including a particular probing technique (e.g.,
,13	four point probe)
716	To determine dimension (e.g., distance or thickness)
717	To determine material composition
718	To detect a flaw or defect
719	With semiconductor or IC materials quality determination using conductivity effects
720	With compensation means
721	For temperature variation
722	Device or apparatus determines conductivity effects
723	Potentiometer
724	Using a probe type structure
725	. Using a particular bridge circuit
726	. Transformer testing (e.g., ratio)
727	 Piezoelectric crystal testing (e.g., frequency, resistance)
66	CONDUCTOR IDENTIFICATION OR LOCATION (E.G., PHASE IDENTIFICATION)
67	 Inaccessible (at test point) conductor (e.g., buried in wall)
160	ELECTRICAL SPEED MEASURING
161	. Speed comparing means
162	. With acceleration measuring means
163	. Including speed analog electrical signal generator
164	Eddy current generator type (e.g., tachometer)
165	With direction indicator
166	. Including speed-related frequency generator
167	Including rotating magnetic field actuated indicator
168	Including periodic switch
169	In ignition system
170	High voltage speed signal type
171	With extent-of-travel indicator
172	Including synchronized recording medium
173	Including magnetic detector

174	Permanent magnet type
175	Including radiant energy detector
176	. Including object displacement varied variable circuit impedance
177	. Including motor current or voltage sensor
178	. Including "event" sensing means
179	Magnetic field sensor
180	Mechanically actuated switch
71.1	DETERMINING NONELECTRIC PROPERTIES BY MEASURING ELECTRIC PROPERTIES
71.2	. Erosion
71.3	. Beam of atomic particles
71.4	. Particle counting
71.5	. Semiconductors for nonelectrical property
71.6	. Superconductors
72	TESTING POTENTIAL IN SPECIFIC ENVIRONMENT (E.G., LIGHTNING STROKE)
72.5	. Voltage probe
73.1	PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
74	TESTING AND CALIBRATING ELECTRIC METERS (E.G., WATT-HOUR METERS)
75	. By stroboscopic means
76.11	MEASURING, TESTING, OR SENSING ELECTRICITY, PER SE
76.12	. Analysis of complex waves
76.13	Amplitude distribution
76.14	Radiometer (e.g., microwave, etc.)
76.15	With sampler
76.16	With counter
76.17	With integrator
76.18	With slope detector
76.19	Frequency spectrum analyzer
76.21	By Fourier analysis
76.22	Real-time spectrum analyzer
76.23	With mixer
76.24	With sampler
76.25	With slope detector
76.26	Scanning-panoramic receiver
76.27	With particular sweep circuit
77.11	Nonscanning
76.28	Digital filter
76.29	With filtering
76.31	Parallel filters
76.32	With space discharge device
76.33	Correlation
76.34	With space discharge device
76.35	
76.36	
76.37	Bragg cell
76.38	

76.39	 Frequency of cyclic current or voltage (e.g., cyclic counting etc.)
76.41	Frequency comparison, (e.g., heterodyne, etc.)
76.42	
76.43	With plural mixers
76.44	
76.45	Bandpass
76.46	Plural
76.47	
76.48	With counter
76.49	Tuned mechanical resonator (e.g., reed,
70.49	piezocrystal, etc.)
76.51	
76.52	By phase comparison
76.53	With phase lock
76.54	
76.55	Digital output
76.56	With microwave frequency detection
76.57	
76.58	With sampler
76.59	With multiplexing
76.61	
76.62	With counter
76.63	Using register
76.64	
76.65	With space discharge device
76.66	
76.67	
76.68	With filtering
76.69	
76.71	
	Qualitative output
76.73	With saturable device
76.74	Deviation measurement
76.75	Having inductive sensing
76.76	With space discharge device
76.77	. Phase comparison (e.g., between cyclic pulse
	voltage and sinusoidal current, etc.)
76.78	Quadrature sensing
76.79	Feedback control, electrical
76.81	Feedback control, mechanical
76.82	Digital output
76.83	Analog output
84	With waveguide (e.g., coaxial cable)
85	With frequency conversion
86	Polyphase (e.g., phase angle, phase rotation or
	sequence)
87	With nonlinear device (e.g., saturable reactor,
	rectifier), discharge device (e.g., gas tube) or lamp
88	Cathode ray

89	Space discharge control means (e.g., grid)
90	Electrodynamometer instrument
91	Synchroscope type
92	. Fluid (e.g., thermal expansion)
93	Conductive field (e.g., mercury)
94	Electrolytic
95	. With waveguide or long line
96	. Using radiant energy
97	Light beam type (e.g., mirror galvanometer, parallax-free scale)
98	 Balancing (e.g., known/unknown voltage comparison, bridge, rebalancing)
99 R	Automatic
100	With recording
99 D	Digital voltmeters
101	. Non-rebalancing bridge
102	. Transient or portion of cyclic
103 R	. Demand, excess, maximum or minimum (e.g., separate meters for positive and negative power, peak voltmeter)
104	Thermal (e.g., actuation)
103 P	Peak voltmeters
105	. Thermal (e.g., compensation)
106	Actuation
107	. Polyphase
108	Positive, negative or zero sequence
109	. Electrostatic attraction or piezoelectric
110	. Meter protection or fraud combatting
111	 With storage means for voltage or current (e.g., condenser banks)
112	Tape, sheet (e.g., disk) or wire (e.g., magnetic) storage
113	. Recording
114	. Plural meters (e.g., plural movements in one case)
115	. Plural ranges, scales or registration rates
116	With register (e.g., discount type, demand penalty)
117 R	. Magnetic saturation (e.g., in field or in amplifier)
117 H	Hall effect
118	. Modulator/demodulator
119	. With rectifier (e.g., A.C. to D.C.)
120	. With voltage or current conversion (e.g., D.C. to A.C., 60 to 1000)
121 R	. Cathode ray (e.g., magic eye)
121 E	Magic eye indicators
122	. Gaseous discharge (e.g., spark gap voltmeter)
123 R	. With amplifier or space discharge device
124	Inverted amplifier
123 C	Feedback amplifiers

125	. Inertia control, instrument damping and vibration damping
126	. With coupling means (e.g., attenuator, shunt)
127	Transformer (e.g., split core admits conductor carrying unknown current)
128	Selective filter
129	 Polepiece (e.g., split) admits nonunitary input conductor
130	. Self-calibration
131	. Suppressed zero
132	. Nonlinear (e.g., Thyrite)
133	 Nonquantitative (e.g., hot-line indicator, polarity tester)
134	 With commutator or reversing or pulsating switch (e.g., D.C. watt-hour meter)
135	Oscillating
136	 With rolling wheel or ball (e.g., transmission, integrating)
137	 Eddy current rotor (e.g., A.C. integrating wattmeter)
138	With phase adjustment
139	 Motor-driven, time-controlled or oscillating (e.g., ratchet)
140 R	. Plural inputs (e.g., summation, ratio)
141	Voltamperes (real or reactive)
142	Watts
140 D	Ratio
143	 Plural active motor elements (e.g., for two crossed pointers)
144	. With electromagnetic field (e.g., dynamometer)
145	Solenoid plunger type
146	With permanent magnet (e.g., field, vane)
147	Soft iron vane
149	. With probe, prod or terminals
150	. Eccentrically pivoted coil
151 R	. With permanent magnet
152	Drag magnet
151 A	Permanent magnet core
153	. With register
154 R	 With rotor (e.g., filar suspension, zero set, balancing)
155	With pivot (e.g., internal friction compensation, anticreep)
154 PB	Pointer and bearing details
156	. Casings
157	. Combined
158.1	MISCELLANEOUS

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